

<b>Notice of References Cited</b>	Application/Control No. 10/787,015		Applicant(s)/Patent Under Reexamination CHIN ET AL.	
	Examiner David M. Naff		Art Unit 1651	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,893,816 B1	05-2005	Beattie, Kenneth L.	435/6
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	D	US-			
	E	US-			
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	K	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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